

Description

The APG40N10DF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = 100V I_{D} = 40A$

 $R_{DS(ON)} < 25 m\Omega \text{ @ } V_{GS} = 10 V \text{ (Type: } 14 m\Omega)$

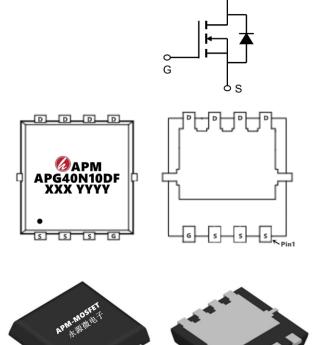
Application

Consumer electronic power supply

Motor control

Synchronous-rectification

Isolated DC



Package Marking and Ordering Information

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Product ID	Pack	Marking	Qty(PCS)	
APG40N10DF	PDFN3*3-8L	APG40N10DF XXX YYYY	5000	

Absolute Maximum Ratings (T_C=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain source voltage	100	V
VGS	Gate source voltage	±20	V
ID	Continuous drain current¹¹, T _C =25 ℃	40	Α
ID, pulse	Pulsed drain current ²⁾ , T _C =25 $^{\circ}$ C	120	А
P _D	Power dissipation ³⁾ , T _C =25 $^{\circ}$ C	71	W
EAS	Single pulsed avalanche energy ⁵⁾	57	mJ
Tstg, Tj	Operation and storage temperature	-55 to 150	$^{\circ}$ C
RθJC	Thermal resistance, junction-case	1.76	°C/W
RθJA	Thermal resistance, junction-ambient ⁴⁾	62	°C/W

APG40N10DF

100V N-Channel Enhancement Mode MOSFET

Electrical Characteristics (T_c=25°C unless otherwise noted)

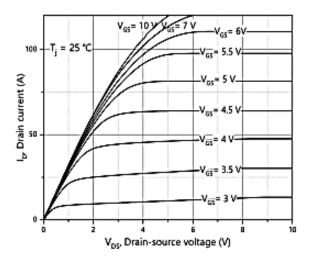
Symbol	Parameter	Test condition	Min.	Тур.	Max.	Unit
BVDSS	Drain-source breakdown voltage	V _{GS} =0 V, I _D =250 μA	100	107		V
VGS(th)	Gate threshold voltage	V_{DS} = V_{GS} , I_D =250 μA	1.2	1.5	2.5	V
RDS(ON)	Drain-source on-state resistance	V _{GS} =10 V, I _D =10 A		14	25.0	mΩ
RDS(ON)	Drain-source on-state resistance	V _{GS} =4.5 V, I _D =7 A		18	30.0	mΩ
IGSS	Gate-source leakage current	V _{GS} =±20 V			±100	nA
IDSS	Drain-source leakage current	V _{DS} =100 V, V _{GS} =0 V			1	uA
Ciss	Input capacitance	V _{GS} =0 V,		1003.9		pF
Coss	Output capacitance	V _{DS} =50 V,		185.4		pF
Crss	Reverse transfer capacitance	f=100 kHz		9.8		pF
td(on)	Turn-on delay time	V_{GS} =10 V, V_{DS} =50 V, R_{G} =10 Ω , I_{D} =5 A		16.6		ns
tr	Rise time			3.8		ns
td(off)	Turn-off delay time			75.5		ns
t _f	Fall time	ID-07A		46		ns
Qg	Total gate charge			16.2		nc
Q _{gs}	Gate-source charge	I _D =5 A,		2.8		nc
Qgd	Gate-drain charge	V _{DS} =50V, V _{GS} =10V		4.1		nc
Vplateau	Gate plateau voltage			3		V
Is	Diode forward current			30		Α
ISP	Pulsed source current	VGS <vth< td=""><td></td><td>90</td><td></td><td>Α</td></vth<>		90		Α
trr	Reverse recovery time		49			ns
Qrr	Reverse recovery charge	I _S =1A, di/dt=100 A/μs	61.8			nc
Irrm	Peak reverse recovery current		2.4			Α

Note:

- 1. Calculated continuous current based on maximum allowable junction temperature.
- 2. Repetitive rating; pulse width limited by max. junction temperature.
- $\ensuremath{\mathtt{3}}_{\times}$ Pd is based on max. junction temperature, using junction-case thermal resistance.
- 4. The value of $R_{\Theta ja}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T_a =25 °C.
- 5、 V_{DD} =50 V, R_G =25 Ω , L=0.3 mH, starting T_j =25 °C.



Typical Characteristics



V_{os} = 10 V

T_j = 25 ℃

| V_{os} = 10 V

V_{os} = 10 V

V_{os} Gate-source voltage(V)

Figure 1, Typ. output characteristics

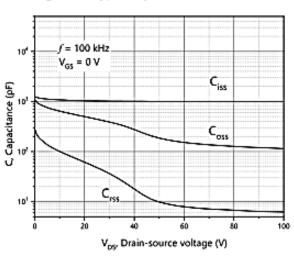


Figure 2, Typ. transfer characteristics

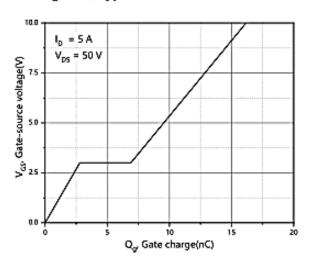


Figure 3, Typ. capacitances

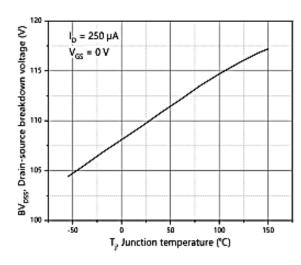


Figure 4, Typ. gate charge

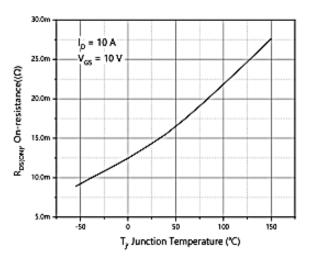
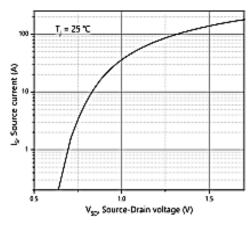


Figure 5, Drain-source breakdown voltage

Figure 6, Drain-source on-state resistance





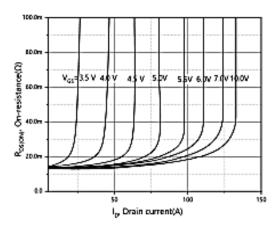
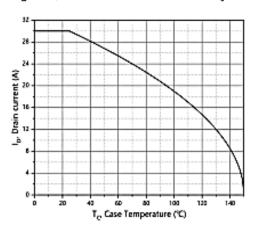


Figure 7, Forward characteristic of body diode

Figure 8, Drain-source on-state resistance



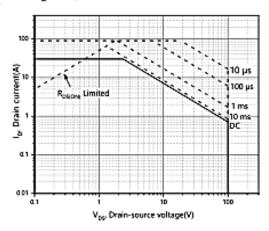
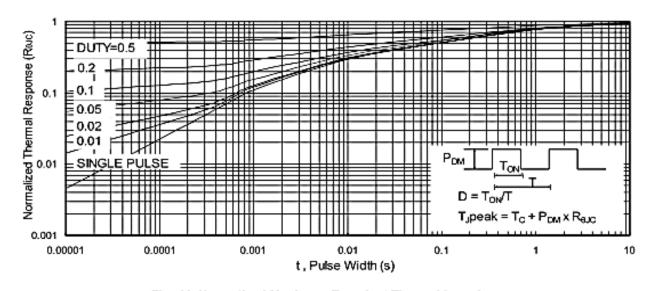


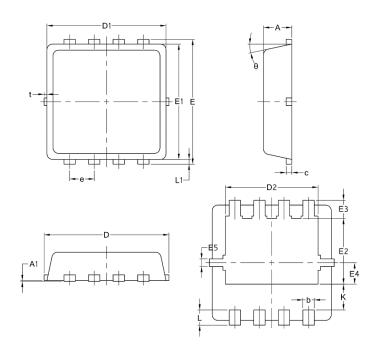
Figure 9, Drain current

Figure 10, Safe operation area T_C=25 *C



Figu11. Normalized Maximum Transient Thermal Impedance





	Common		
Symbol		mm	
	Mim	Nom	Max
А	0.70	0.75	0.85
A1	/	/	0.05
b	0.20	0.30	0.40
С	0.10	0.152	0.25
D	3.15	3.30	3.45
D1	3.00	3.15	3.25
D2	2.29	2.45	2.65
E	3.15	3.30	3.45
E1	2.90	3.05	3.20
E2	1.54	1.74	1.94
E3	0.28	0.48	0.65
E4	0.37	0.57	0.77
E5	0.10	0.20	0.30
е	0.60	0.65	0.70
K	0.59	0.69	0.89
L	0.30	0.40	0.50
L1	0.06	0.125	0.20
t	0	0.075	0.13
Φ	10	12	14



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Edition	Date	Change
Rve1.0	2018/11/10	Initial release

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